

SEMICONDUCTOR TEST SYSTEM AND METHOD

ABSTRACT

The invention(s) relates to semiconductor test system and method that isolates and counteracts forces that bend test equipment resulting in improved manufacturing yield and throughput. The system includes a force retainer fixedly mounted on a material handler and a force locator positioned between the force retainer and a circuit board. Together, the force retainer and locator prevent the circuit board from bending. Other embodiments are illustrated and described.

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